


<b>Search Notes</b>  	<b>Application/Control No.</b>  09639196	<b>Applicant(s)/Patent Under Reexamination</b>  PALIN, ARTO
	<b>Examiner</b>  Nguyen, Hau H	<b>Art Unit</b>  2628

SEARCHED			
Class	Subclass	Date	Examiner
345	1.1, 1.2, 2.1, 2.3	12/6/08	HN
455	41.2, 41.3, 557, 556, 566		
348	552, 555		
715	716-718, 961		

SEARCH NOTES		
Search Notes	Date	Examiner
EAST Search US-PGPUB; USPAT; FPRS; EPO; JPO; IBM_TDB text search updated and attached	12/6/08	HN

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

	/HAU H NGUYEN/ Primary Examiner, Art Unit 2628
--	---